High-harmonic generation and EUV Science

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Advanced Research Center for Nanolithography (ARCNL), Amsterdam, The Netherlands. EUV source workshop, 04.11.2019, Amsterdam, The Netherlands.



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Ultrafast and ultrasmall

• Ultrashort pulses

Small structures

• Short wavelengths



High-harmonic generation enables (sub-) fs time resolution and nm spatial resolution! (but is not suitable as a source for lithography)





An outside look at HHG







An outside look at HHG

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Double Gaussian beam profile; pulse energy is lost in wings. Broad wings prohibit imaging of embedded structures.

An inside look into HHG



For each generated energy there are two electron trajectories contributing: *Long and short trajectories*

HHG and EUV science

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Trajectory selection in two-color HHG

Adding an orthogonally polarized 400nm pulse changes the trajectories of the electrons.







S. Roscam Abbing et al., arXiv:1910.06470 [physics.optics] (2019).

Divergence in HHG



Adding a perpendicular 400 nm pulse to the generation process enables divergence control.

When selecting short trajectories, the total photon flux increases as well!

The optics are easy to implement.

The scheme enables micro-focussing of HHG

Divergence in HHG





<u>Poster:</u> "Divergence Control of High-harmonic Generation Enables Highbrightness extreme-ultraviolet sources" by Sylvianne Roscam Abbing

Preprint: S. Roscam Abbing et al., arXiv:1910.06470 [physics.optics] (2019).

Exposure kinetics of photoresists

1. Time-resolved extreme-ultraviolet transient absorption

2. Time-resolved extreme/deep-ultraviolet luminescence





XUV Absorption and exposure in a single setup

Measure the complex dynamics in materials relevant for EUV lithography and understand how to improve them.



Unique feature of HHG-XANES: Simultaneous exposure and spectrally resolved absorption spectroscopy in the XUV with chemical sensitivity.

ARCNL Objective: Measure exposure kinetics as function of dose in photoresists.

Spectroscopy of EUV materials with HHG





XUV absorption tracks photochemistry

Exposure and absorption spectroscopy of tin-oxo cages from 25-45 eV: Follow 4d-LUMO transitions in Sn (25-30 eV).





ΘOH

HO Θ \oplus

Luminescence of metal-oxo photoresists

Energy converted into luminescence will not drive a chemical reaction.





Time-resolving the luminescence



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Observation of sub-nanosecond radiative relaxation



Mono-exponential for Carbazol: 3.2 ns (Carb) Bi-exponential for cluster: 0.54 & 2.8 ns (TiO-Carb) Possible hint at additional decay channel and charge transfer. Ongoing: Extension of technique to extreme ultraviolet excitation.





Conclusions

- 1. Developed experimental method for divergence control of high-harmonic generation.
- 2. Used table-top extreme ultraviolet absorption to follow the exposure kinetics of a photoresist.
- 3. Used time-resolved luminescence to identify alternative decay channels besides chemical reactions.







Outlook

New schemes for HHG:

- Solid-state HHG
- High-flux water-window soft x-ray HHG

Time-resolved experiments on EUVL materials:

- Time-resolved XUV-excited optical luminescence
- Ultrafast pump-probe spectroscopy





Thank You!

HHG and EUV science group at **ARCNL:** Sylvianne Roscam Abbing Maarten van der Geest Filippo Campi **Reinout Jaarsma** Najmeh Sadegh (not in picture, **Brouwer group**) Faegheh Sajjadian (until Jan 2019) ZhuangYan Zhang (not in picture) **Evelien Wooning (not in picture,** until Aug 2019) Alexandra Zeltsi (not in picture)

Ongoing collaborations at ARCNL: Sonia Castellanos Fred Brouwer



